

US00D784170S

(12) **United States Design Patent** (10) **Patent No.:** **US D784,170 S**
Kamiyama et al. (45) **Date of Patent:** **** Apr. 18, 2017**

(54) **DIAL GAUGE INSPECTION MACHINE**

OTHER PUBLICATIONS

(71) Applicant: **MITUTOYO CORPORATION**,
Kawasaki, Kanagawa (JP)

Catalog of Optimar 100, "Universal Dial Indicator Testing Machine," Mahr GmbH Göttingen, Jun. 30, 2010.

(72) Inventors: **Shuichi Kamiyama**, Yokohama (JP);
Yoshinosuke Murai, Kawasaki (JP); **Yu Sugai**, Hadano (JP); **Shigeru Ohtani**,
Kawasaki (JP)

"i-Checker Full/Semi-Automatic Inspection System," Mitutoyo Product News, Bulletin No. 1563, Mitutoyo America Corporation, Nov. 2002.

* cited by examiner

(73) Assignee: **MITUTOYO CORPORATION**,
Kawasaki (JP)

Primary Examiner — Antoine D Davis

(74) *Attorney, Agent, or Firm* — Oliff PLC

(**) Term: **15 Years**

(21) Appl. No.: **29/554,321**

(57) **CLAIM**

(22) Filed: **Feb. 10, 2016**

The ornamental design for a dial gauge inspection machine, as shown and described.

(30) **Foreign Application Priority Data**

Sep. 30, 2015 (JP) 2015-021574

(51) **LOC (10) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/61**

(58) **Field of Classification Search**
USPC D10/61, 70
CPC G01B 3/22; G07F 17/32
See application file for complete search history.

DESCRIPTION

FIG. 1 is a perspective view of a dial gauge inspection machine;

FIG. 2 is a front view thereof;

FIG. 3 is a rear view thereof;

FIG. 4 is a left-side view thereof;

FIG. 5 is a right-side view thereof;

FIG. 6 is a top view thereof; and,

FIG. 7 is a bottom view thereof.

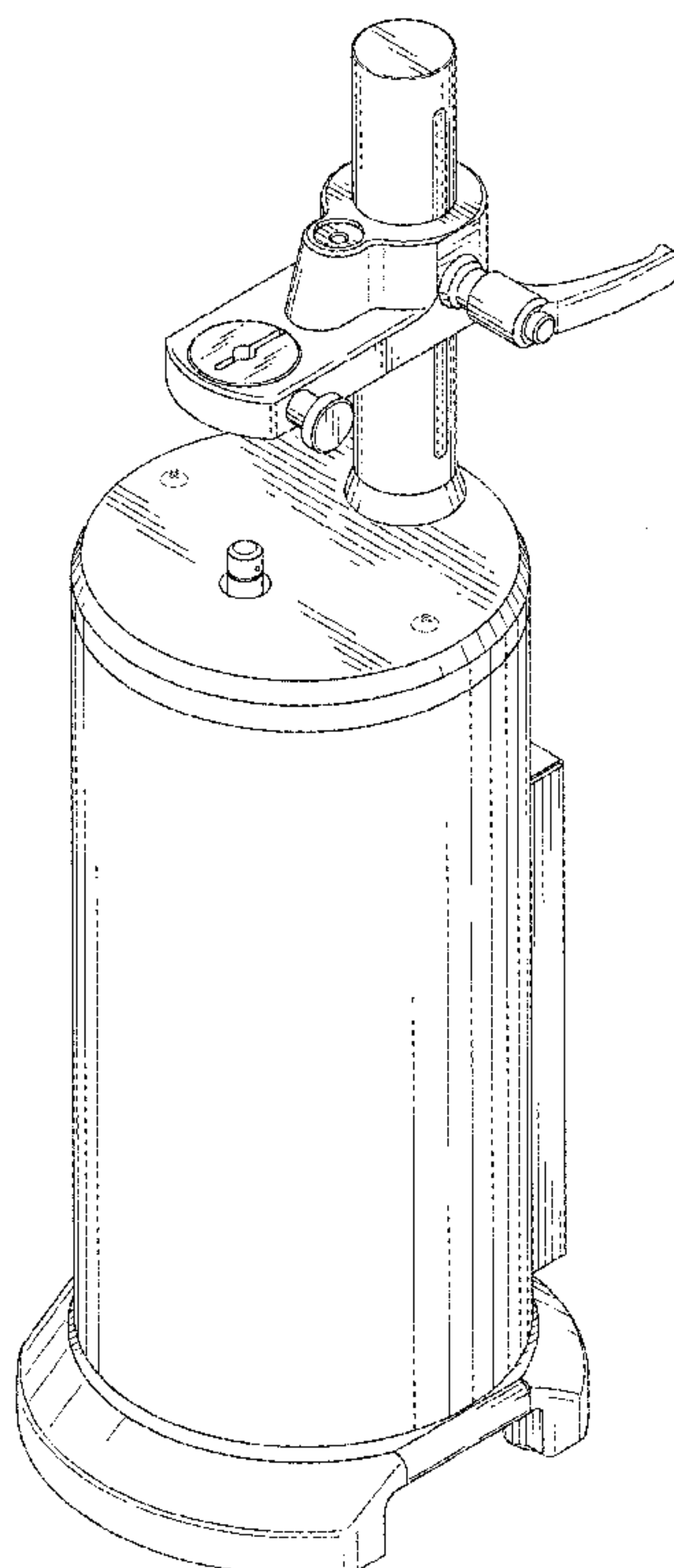
The broken lines depict environmental subject matter only and form no part of the claimed design.

(56) **References Cited**

U.S. PATENT DOCUMENTS

8,092,293 B2 * 1/2012 Richards G07F 17/32
463/17

1 Claim, 6 Drawing Sheets



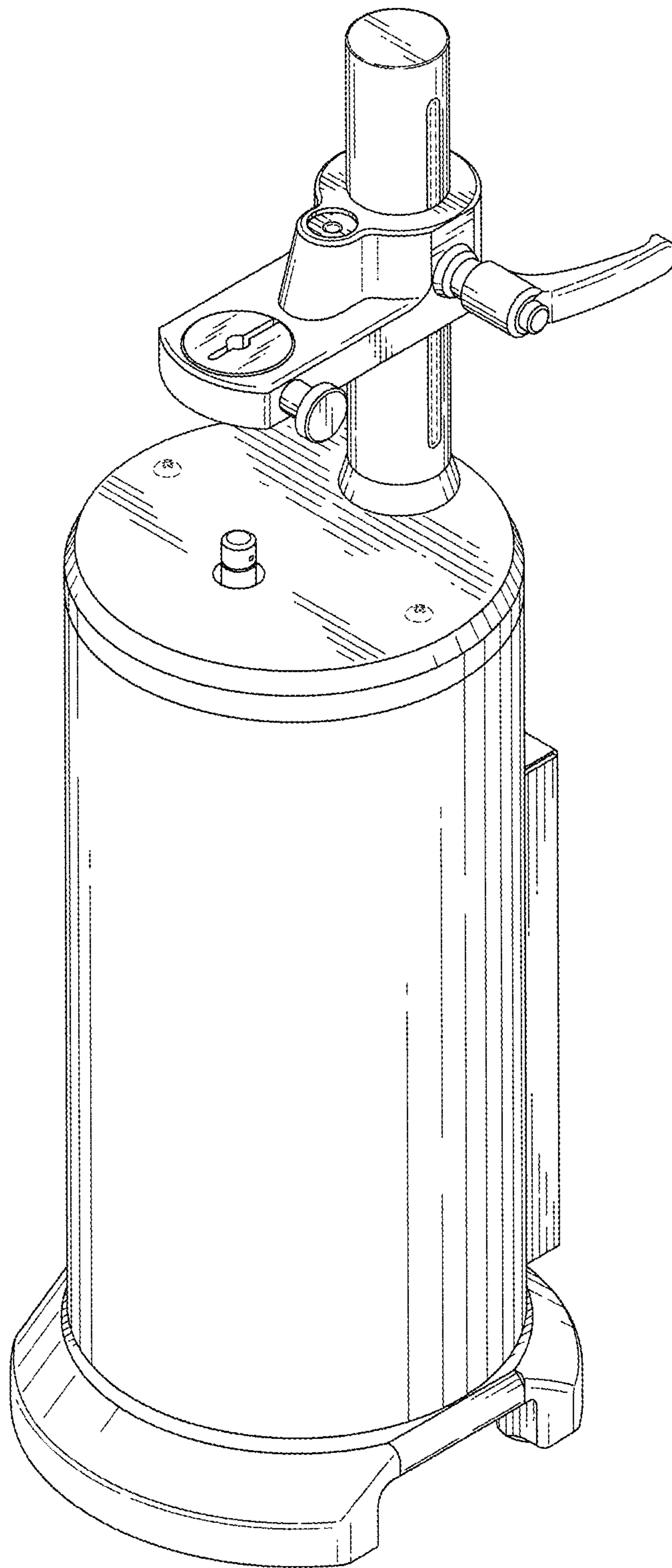


FIG. 1

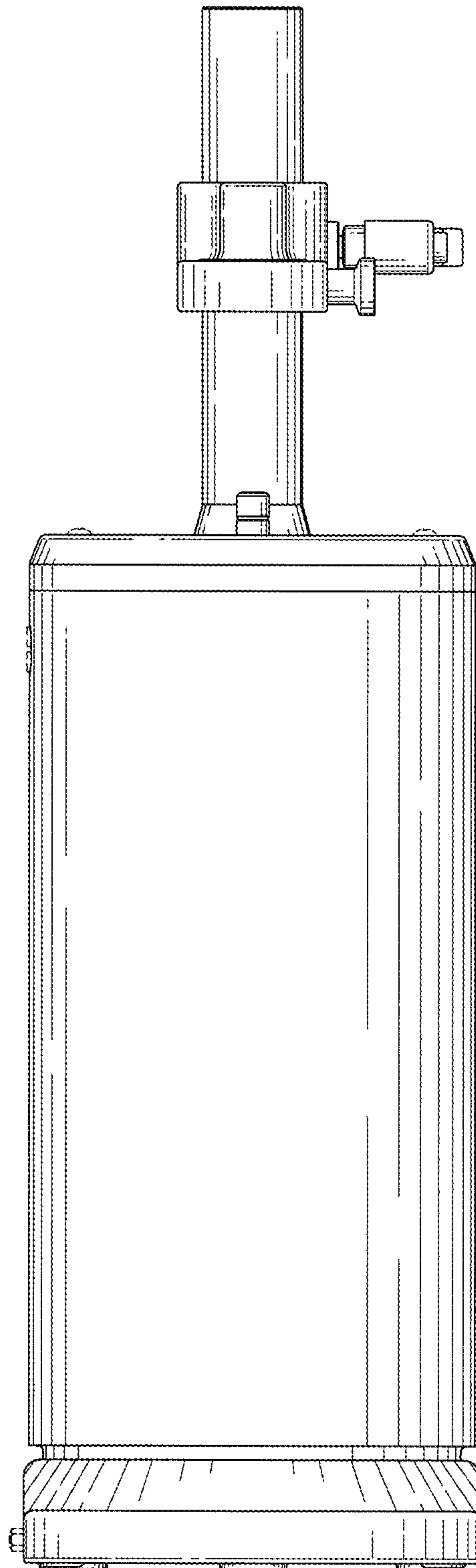


FIG. 2

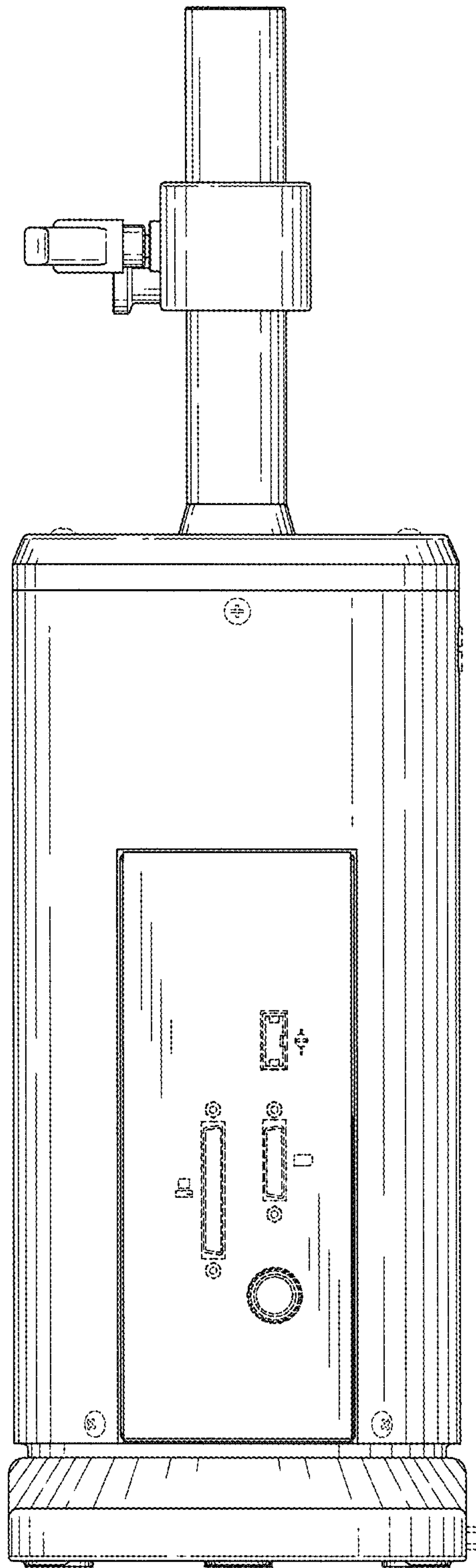


FIG. 3

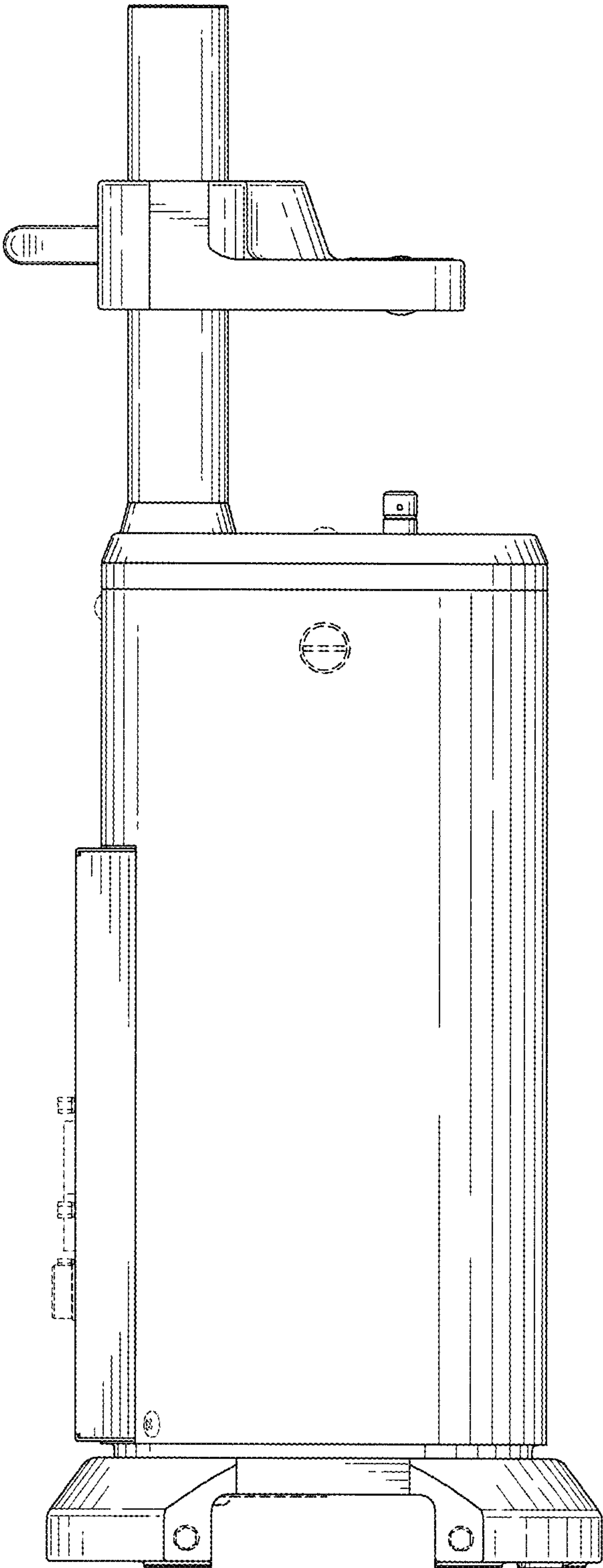


FIG. 4

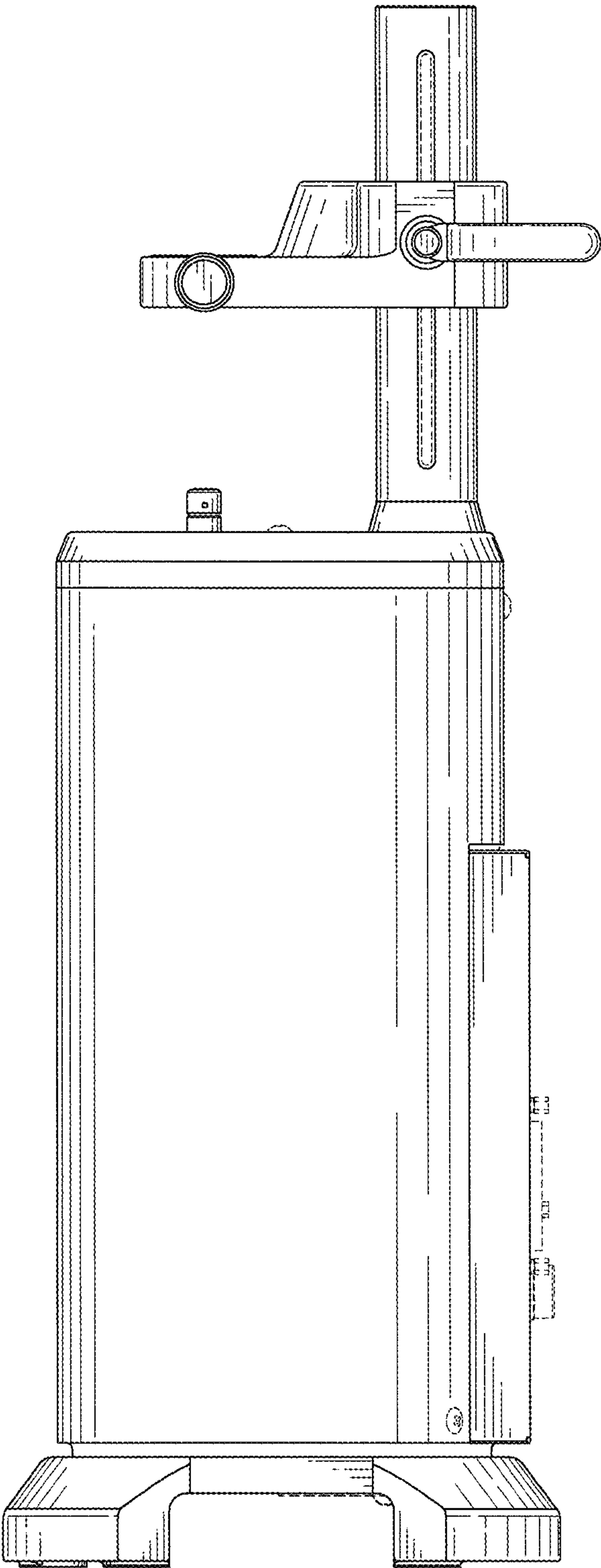


FIG. 5

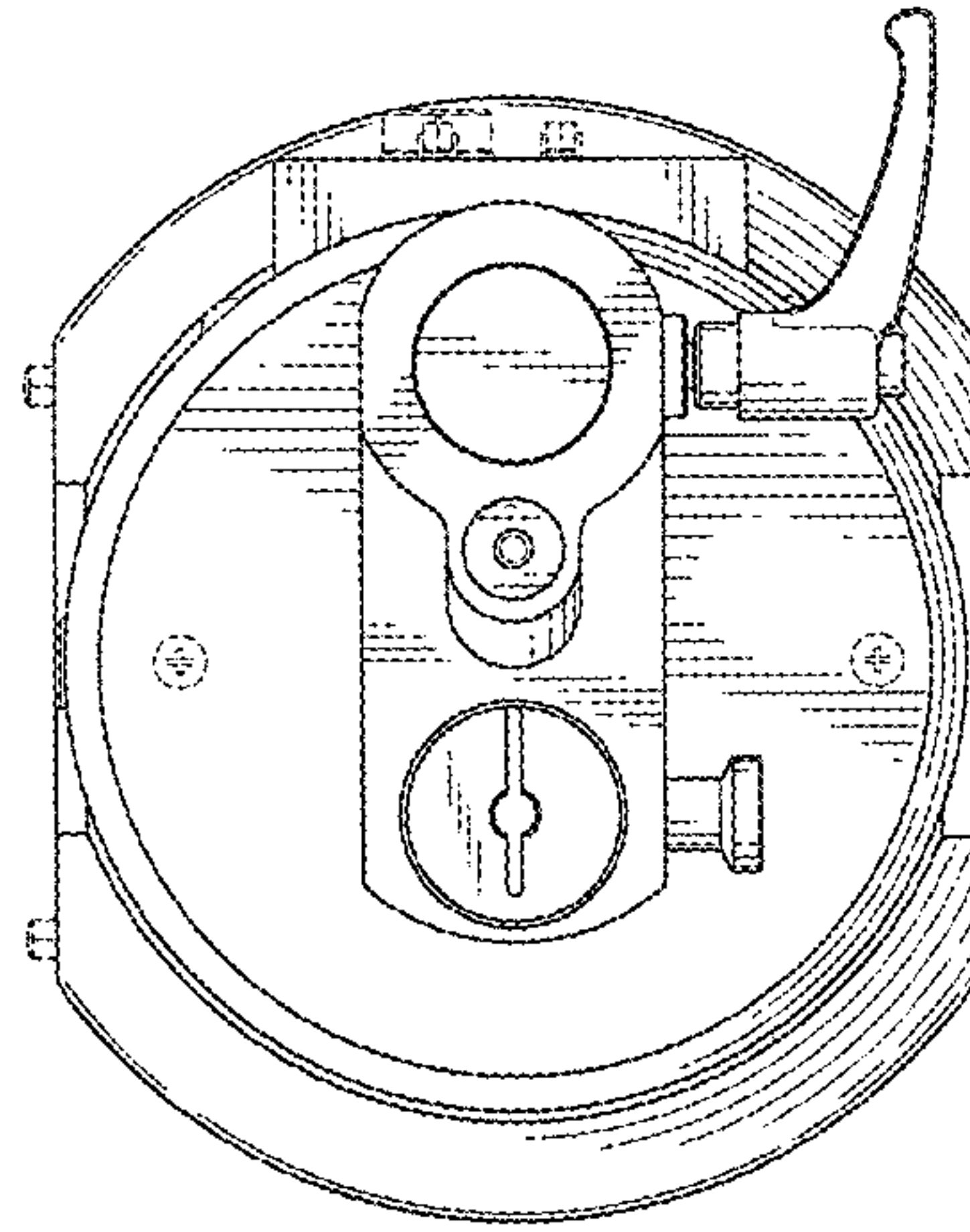


FIG. 6

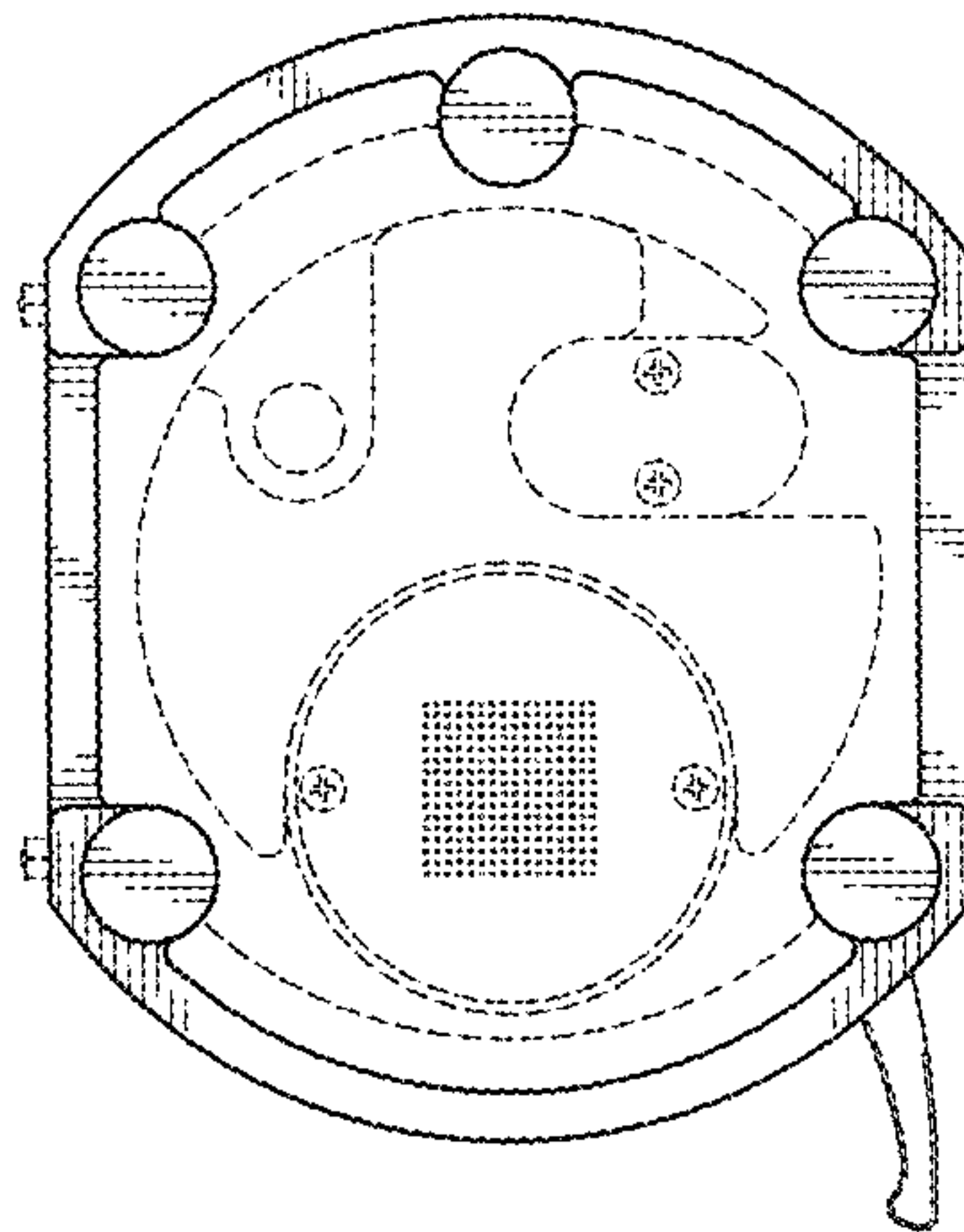


FIG. 7